

Measurement of: Elemental analysis, oxidation states, valence band, and surface morphology of the materials.

Equipment: MULTIPROBE Surface analysis system (MPSAS).

Property Measured: The system mainly consist of techniques such as X-ray photoelectron spectroscopy (XPS), Ultraviolet photoelectron spectroscopy, VT-Atomic force microscopy, VT- Scanning tunnelling microscopy along with heating cooling facility for measurements.

Photograph (small size):



Basic Principle: It is a multi-technique system consisting of state-of-the art surface sensitive techniques to analyze the elemental analysis, oxidation states, valence band, and surface morphology of the materials.

Capabilities: The rigid construction of the system is perfectly designed to ensure maximum stability for high resolution microscopy and spectroscopy. The technique is capable of analyzing samples including metals, semiconductors, Dielectric materials, Thin films, nanostructures, etc.

Sample Requirement: Sample should be UHV compatible and non hazardous.